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Equation (2) in the original article1 was incorrect. The correct equation should read

$$\delta f (k, A) = \sqrt{\frac{f_0 k_B T B}{\pi k Q A^2}} + \frac{2n_{as}^2 B^3}{3A^2}. \quad (2)$$

This correction does not affect any other contents of the original article.


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